

4/17/2013



**RELIABILITY MONITOR REPORT
FOR**

MFN 5 μ m Silicon Gate CMOS HV (S5HV)

MAXIM INTEGRATED

**160 RIO ROBLES
SAN JOSE, CA 95134**

**This Report was prepared by
MAXIM INTEGRATED Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX313LESE+	MAX5048CAUT
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The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 6697 QUANTITY: 180 FAILS: 0 FITS: 17.0

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2012 and 3/31/2013 .

Process Information:

Process Description: MFN 5µm Silicon Gate CMOS HV (S5HV)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1235	MAX5048CAUT+	135°C	192 HRS	45	0	N031AA026JQ
HIGH TEMP OP LIFE	1235	MAX5048CAUT+	135°C	192 HRS	45	0	N031AA026IQ
HIGH TEMP OP LIFE	1235	MAX5048CAUT+	135°C	192 HRS	45	0	N031AA026HQ
HIGH TEMP OP LIFE	1235	MAX5048CAUT+	135°C	192 HRS	45	0	N031AA026GQ
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1230	MAX313LESE+	-65C TO 150C	1000 CYS	80	0	N6U1BA111M#
Total:						0	

UNBIASED MOISTURE RESISTANCE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
MOISTURE SOAK	1230	MAX313LESE+	130C, 85% R.H.	100 HRS	80	0	N6U1BA111M#
Total:						0	

FAILURE RATE: MTTF (YRS): 6697 QUANTITY: 180 FAILS: 0 FITS: 17.0